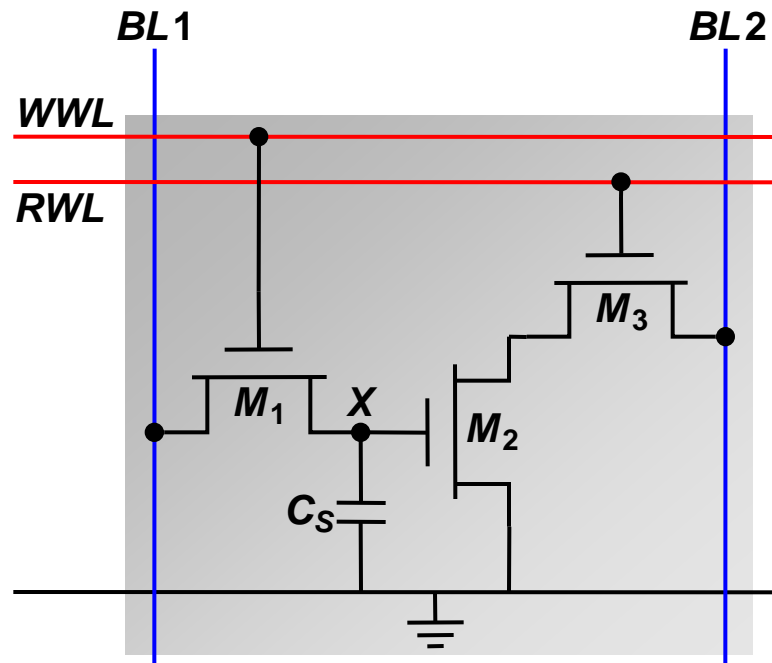


*EE466/586*  
*VLSI Design*

**Partha Pande**  
**School of EECS**  
**Washington State University**  
**pande@eecs.wsu.edu**

***Lecture 26***  
***Memory Design (Cont'd)***

# 3-Transistor DRAM Cell



No constraints on device ratios

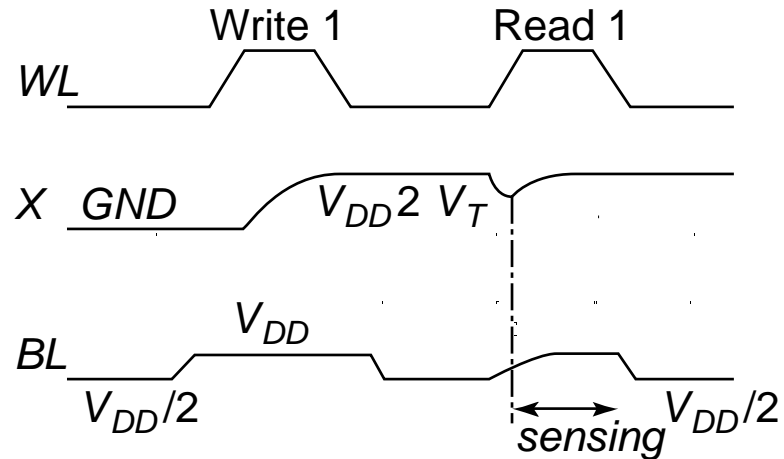
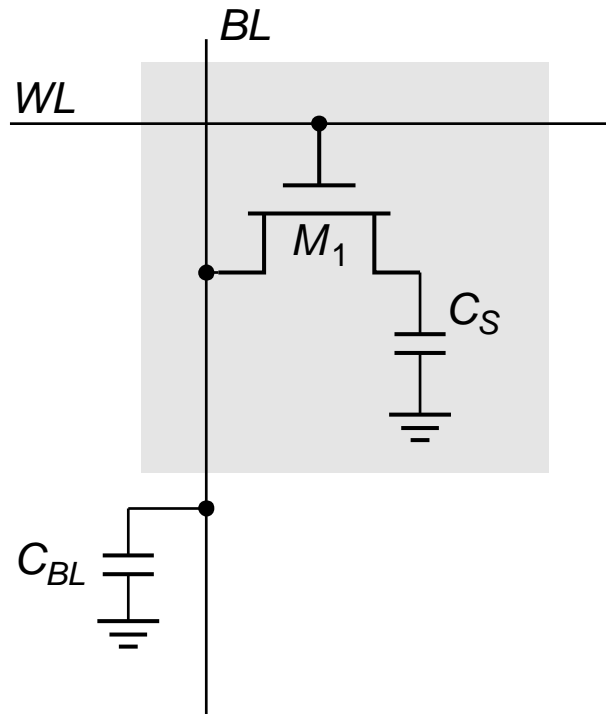
Reads are non-destructive

Value stored at node X when writing a “1” =  $V_{WWL} - V_{Tn}$

# 3-Transistor DRAM Cell

- ❑ Precharge both the columns
- ❑ Assert the *write word line* (WWL)
- ❑ The data is retained as charge on capacitance  $C_S$  once WWL is lowered
- ❑ When reading the cell, the *read-word line* (RWL) is raised
- ❑ If “1” is stored then  $BL_2$  will be discharged through  $M_3$  and  $M_2$
- ❑ If “0” is stored then there will be no conducting path,, so the precharged high level of  $BL_2$  will not change significantly.

# 1-Transistor DRAM Cell



**Write:**  $C_S$  is charged or discharged by asserting WL and BL.

**Read:** Charge redistribution takes places between bit line and storage capacitance

$$\Delta V = V_{BL} - V_{PRE} = V_{BIT} - V_{PRE} \frac{C_S}{C_S + C_{BL}}$$

**Voltage swing is small; typically around 250 mV.**

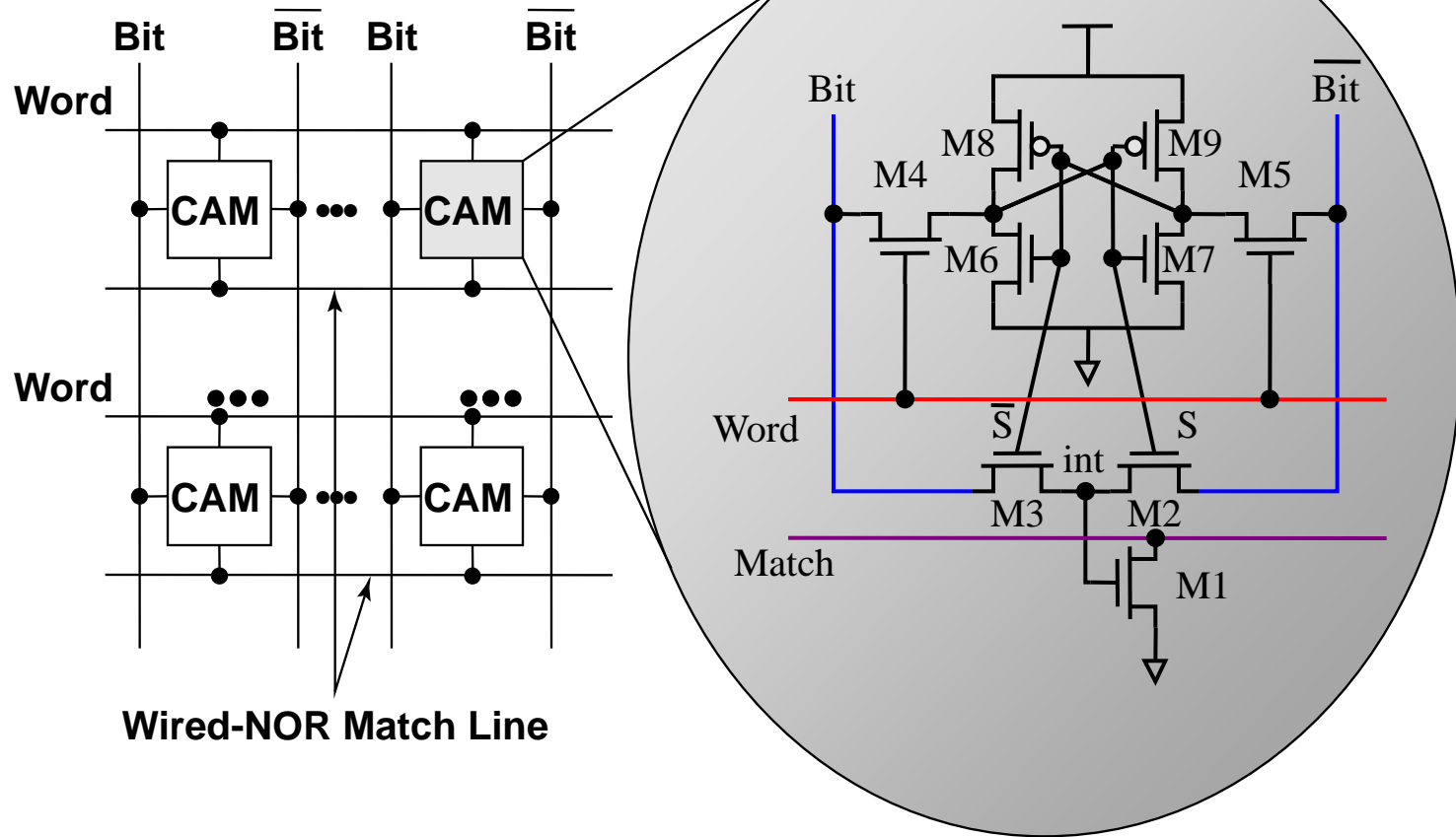
# *DRAM Cell Observations*

- ❑ 1T DRAM requires a sense amplifier for each bit line, due to charge redistribution read-out.
- ❑ DRAM memory cells are single ended in contrast to SRAM cells.
- ❑ The read-out of the 1T DRAM cell is destructive; read and refresh operations are necessary for correct operation.
- ❑ Unlike 3T cell, 1T cell requires presence of an extra capacitance that must be explicitly included in the design.
- ❑ When writing a “1” into a DRAM cell, a threshold voltage is lost. This charge loss can be circumvented by bootstrapping the word lines to a higher value than  $V_{DD}$

# *Content-Addressable Memories (CAMs)*

- ❑ In SRAMs the access mechanism is based on known address.
- ❑ But there are applications where the data we seek is associated with a known binary keyword rather than a known binary address.
- ❑ The known keyword is compared against previously stored keywords, called tags, that reference the actual data we seek
- ❑ The tags are not stored in any particular order so we must match the address keyword with the tags that are already stored to access the desired data.

# Static CAM Memory Cell





# *Principle*

- ❑ The array contains n-bit stored tags that are to be compared with the incoming n-bit keyword.
- ❑ Each row holds a different tag
- ❑ Each bit of the tag is stored in a separate 6T SRAM cell.
- ❑ Match lines are pre charged high
- ❑ If there is a match, the match line remains high
- ❑ If the keyword and stored tag do not match, the NMOS device discharges the match line.

# *CAM in Cache Memory*

